

УНИВЕРЗИТЕТ У БЕОГРАДУ
ИНСТИТУТ ЗА ФИЗИКУ БЕОГРАД
ИНСТИТУТ ОД НАЦИОНАЛНОГ ЗНАЧАЈА ЗА РЕПУБЛИКУ СРБИЈУ
Прегревница 118, 11080 Земун - Београд, Република Србија
Телефон: +381 11 3713000, Факс: +381 11 3162190, www.ipb.ac.rs
ПИБ: 100105980, Матични број: 07018029, Текући рачун: 205-66984-23



ПРИМЛ ЕНО			
Рад. јед.	Б р о ј	А р х и в и р а н о	П р и л о г
0801	383/1		

Директору Института за физику у Београду
др Александру Богојевићу

Предмет: Молба за продужење радног односа

Поштовани директоре,

Пошто 10. јуна 2019. године пуним 65 година живота, желео бих да Вам упутим молбу за продужење радног односа за још две године, што је у складу са важећим законским прописима.

Током своје научне каријере учествовао сам на великом броју националних и међународних пројеката који су финансирани од стране Министарства просвете, науке и технолошког развоја. Тренутно сам ангажован на пројекту основних истраживања "Нелинеарна фотоника нехомогених средина и површина". У својству гостујућег професора боравио сам на бројним Универзитетима, између осталих и на: Pohang University of Science and Technology у Похангу, Ј. Кореја (2004-2005), Middle East Technical University у Анкари, Турска (2012), Comenius University у Братислави, Р. Словачка (више пута у периоду 2011-2018) где сам и добио Националну стипендију словачке академије наука (2017). Био сам аутор/коаутор на више од 90 радова у међународним часописима (од тога 85 са ISI листе), 7 поглавља у монографијама и више од 30 предавања по позиву на међународним конференцијама. Један сам од помоћника едитора међународног часописа са ISI листе- Open Physics (раније Central European Journal of Physics). Рангиран сам у категорију А1 код Министарства за просвету, науку и технолошки развој.

УНИВЕРЗИТЕТ У БЕОГРАДУ
ИНСТИТУТ ЗА ФИЗИКУ БЕОГРАД
ИНСТИТУТ ОД НАЦИОНАЛНОГ ЗНАЧАЈА ЗА РЕПУБЛИКУ СРБИЈУ
Прегревица 118, 11080 Земун - Београд, Република Србија
Телефон: +381 11 3713000, Факс: +381 11 3162190, www.jp.ac.rs
ПИБ: 100105980, Матични број: 07018029, Текући рачун: 205-66984-23



Руководио сам израдом 3 докторске дисертације (две одбрањене на Електротехничком факултету Универзитета у Београду и једне одбрањене на Војнотехничкој академији у Београду), као и више магистарских и дипломских радова. Тренутно учествујем у изради једног дела докторске дисертације Јадранке Васиљевић, истраживача приправника Института за физику у Београду, чија се одбрана очекује почетком 2020. године на Физичком факултету Универзитета у Београду.

У Београду, 15.3.2019. године

С поштовањем,

др Бранислав Рађеновић

научни саветник

Izabrani radovi

1. **B. Radjenović**, M. Radmilović-Radjenović and M. Mitrić, Nonconvex Hamiltonians in three dimensional level set simulations of the wet etching of silicon, *Appl. Phys. Lett.* 89 (2006) 213102 (2pp). **IF=4.308**
2. **B. Radjenović**, J. K. Lee and M. Radmilović-Radjenović, Sparse field level set method for non-convex Hamiltonians in 3D plasma etching profile simulations, *Computer Physics Communications* 174 (2006) 127.
3. **B. Rađenovic**, M. Radmilovic-Rađenovic and M. Mitric, Level set Approach to Anisotropic Wet Etching of Silicon, *Sensors* 10 (2010) 4950.
4. **B. Radjenović** and M. Radmilović-Radjenović, An application to the three-dimensional simulations of the Bosch process, *Journal Mater. Res.* 27 (2012) 793.
5. **B. Radjenović** and M. Radmilović-Radjenović, Three different mechanisms of the smoothing of the rough nanostructure, *Electronic Materials Letters* 8 (2012) 491.
6. **B. Radjenović** and M. Radmilović-Radjenović, The effect of different etching modes on the smoothing of the rough surfaces, *Materials Letters*, 8 (2012) 165.
7. **B. Radjenović**, M. Radmilović-Radjenović, The Effect of Plasma Etching on the Surface Topography of Niobium Superconducting Radio Frequency Cavities, *Electron. Mater. Lett.* 10 (2014) 1043. **IF=3.977**
8. **B. Radjenović**, M. Radmilović-Radjenović, Excitation of Confined Modes in Silicon Slotted Waveguides and Microring Resonators for Sensing Purposes, *IEEE Sensors Journal* 14 (2014) 1412.
9. M. Smiljanić, **B. Radjenović**, M. Radmilović-Radjenović, Ž. Lazić, V. Jović, Simulation and experimental study of maskless convex corner compensation in TMAH water solution, *J. Micromech. Microeng.* 24 (2014) 115003.
10. M. Sabo, M. Malaskova, **B. Radjenovic**, O. Harmathova and S. Matejcik, Direct Liquid Sampling for Corona Discharge Ion Mobility Spectrometry, *Anal. Chemistry* 87 (2015) 7389. **IF=5.886**
11. **B. Radjenović**, M. Radmilović-Radjenović and P. Beličev, Eigenmodes of finite length silicon-on-insulator microring resonator arrays, *Opt. Quant. Electron.* 49 (2017) 149.
12. M. Klas, L. Moravsky, Š. Matejcik, **B. Radjenović**, M. Zahoran and M. Radmilović-Radjenović, The breakdown voltage characteristics of compressed ambient air microdischarges from direct current to 10.2 MHz, *Plasma Sources Sci. Technol.* 26 (2017) 055023. **IF=3.939**
13. M. Klas, Š. Matejcik, L. Moravsky, **B. Radjenovic** and M. Radmilovic-Radjenovic, Field-emission enhanced breakdown in oxygen microdischarges from direct-current to radio-frequencies, *Europhys. Lett.* 120 (2017) 25002.
14. M. Radmilović-Radjenović, **B. Radjenović**, Eigenmode and frequency domain analysis of the third-order microring filters, *Opt. Quant. Electron.* 50 (2018) 233.
15. M. M. Smiljanic, Ž. Lazić, **B. Radjenovic**, M. Radmilovic-Radjenovic, Vesna Jovic, Evolution of Si Crystallographic Planes-Etching of Square and Circle Patterns in 25 wt % TMAH, *Micromachines* 10 (2019) 102.

Poglavlja u monografijama

1. **B. Radjenović** and M. Radmilović-Radjenović

Introduction to Differential Forms and its Application to the Finite Element Method in Electromagnetism
FINITE ELEMENTS (WSEAS Press, 2007) (ISSN: 1790-5177) pp. 128-137.

2. **B. Radjenović** and M. Radmilović-Radjenović

Hamilton-Jacobi equation with non-convex Hamiltonians in three dimensional level set simulations of the wet etching of silicon

COMPUTATIONAL CHEMISTRY and APLICATIONS in CHEMISTRY (WSEAS Press, 2007) (ISSN: 1790-2769) pp. 48-51.

3. M. Radmilović-Radjenović , Z.Lj. Petrović and **B. Radjenović**

Modelling of breakdown behavior by PIC/MCC code with improved secondary emission models
Journal of Physics:Conference Series **71** (2007) 012007 (19 pages).

4. **B. Radjenović** and M. Radmilović-Radjenović

3D Etching profile evolution simulations: Time dependence analysis of the profile charging during SiO₂ etching in plasma

Journal of Physics:Conference Series **86** (2007) 012017 (13 pages).

5. **B. Radjenović**

3D Level Set Anysotropic Etching Profile Evolution Simulations

Book Series: Recent Advances in Electrical Engineering (WSEAS Press, 2008), 110-115
(ISBN: 978-960-6766-79-4) (ISSN: 1790-5117)

6. M. Radmilović-Radjenović, B. Sismanoglu, **B Radjenovic** and K. Grigorov

A Particle-in-cell simulations of the breakdown voltage characteristics in argon discharges

Argon: Production, Characteristics and Applications (Nova Science Publishers, Inc. , 2013) 161-188,
(ISSN: 978-1-62618-243-1)

7. P. Beličev, R. Balvanovc, V. Alexandro, N. Kazarinov and **B. Radjenović**

Aspects of multi charged argon beam transport

Argon: Production, Characteristics and Applications (Nova Science Publishers, Inc., 2013) 139-160,
(ISSN: 978-1-62618-243-1)

Radovi publikovani u časopisima

1. Z. Djurić, **B. Radjenović**, Rise time of silicon PIN photodiodes, *Solid-St. Electronics* 26, (1983), 1143-1149.
2. Z. Djurić, M. Smiljanić, **B. Radjenović**, The application of Ramo's theorem to the impulse response calculation of a reach-through avalanche photodiode, *Solid-St. Electronics* 27, (1984), 833-835.
3. **B. Radjenović**, M. Cvijetić, Time response of long wavelength PIN photodiodes based on GaInAs, *J. Opt. Commun.* 5, (1984), 100-103.
4. **B. Radjenović**, D. Tjapkin, The influence of the hybridization of the impurity and the conduction bands on the density of states of doped semiconductors, *Phys. Stat. Sol. (b)* 156, (1989), 487-495.
5. **B. Radjenović**, D. Tjapkin, Temperature dependence of the Fermi level in the two-zone hybrid model of doped semiconductors, *Semicond. Sci. Technol.* 5, (1990), 299-304.
6. D. Tjapkin, **B. Radjenović**, Electrical conductivity of doped semiconductors: the two-zone hybrid model approach, *Semicond. Sci. Technol.* 6, (1991), 857-861.
7. Z. Savić, **B. Radjenović**, M. Pejović, N. Stojadinović, The contribution of border traps to the threshold voltage shift in pMOS dosimetric transistors, *IEEE Trans. Nucl. Sci.* 42, (1995), 1445-1454.
8. D. Tjapkin, V. Milanovic V, Z. Ikonc and **B. Radjenovic**, Electronic and optical properties of semiconductor quantum wells and superlattices, *Materials Science Forum* 214, (1996), 33-40.
9. Z. Savić, **B. Radjenović**, A method for separating the effects of interface from border and oxide trapped charge densities in MOS transistors, *Microelectron. Reliab.* 37, (1997), 1147-1150.
10. M. Radmilović-Radjenović and **B. Radjenović**, Modeling of a low-pressure argon breakdown in combined fields, *Plasma Sources Science and Technology*, 15 (1), (2006), 1-7.
11. M. Radmilović-Radjenović and **B. Radjenović**, The effect of magnetic field on the electrical breakdown characteristics, *J. Phys. D:Appl. Phys.*, 39, (2006), 3002-3007.
12. **B. Radjenović**, M. Radmilović-Radjenović and M. Mitrić, Nonconvex Hamiltonians in three dimensional level set simulations of the wet etching of silicon, *Appl. Phys. Lett.* 89, (2006), 213102 (2pp).
13. **B. Radjenović**, J. K. Lee and M. Radmilović-Radjenović, Sparse field level set method for non-convex Hamiltonians in 3D plasma etching profile simulations, *Computer Physics Communications*, 174, (2006), 127-132.
14. M. Radmilovic-Radjenovic, Z. Lj. Petrovic, G. N. Malovic, D. Maric and **B. Radjenovic**, Modelling of low-pressure gas breakdown in uniform DC electric field by PIC technique with realistic secondary electron emission, *C. Journal of Physics* 56 (2006), Suppl. B 996-1001.
15. **B. Radjenović**, M. Radmilović-Radjenović and P. Beličev, 3D Simulations with Fields and Particles, *WSEAS Trans. on Information Science and Applications*, 3(5), (2006), 869-884.
16. M. Radmilovic-Radjenovic, A. Stojkovic, Z.Lj. Petrovic, A. Strinic, V. Stojanovic, and **B. Radjenovic**, Modeling of Plasma Etcher for Charging Free Processing of Nanoscale Structures, *Materials Science Forum* 518, (2006) 57-62.
17. M. Radmilović-Radjenović and **B. Radjenović**, The influence of the ion-enhanced field emission on microwave breakdown in microgaps, *Plasma Sources Sci. Technol.* 16 (2007), 337-340.

18. M. Radmilović-Radjenović and **B. Radjenović**, A Particle-in-Cell Simulation of the High-Field Effect in Devices With Micrometer Gaps, *IEEE Transaction on Plasma Science*, 35 (5) (2007), 1223-1228.
19. M. Radmilović-Radjenović and **B. Radjenović**, A particle-in-cell simulation of the breakdown mechanism in microdischarges with an improved secondary emission model, *Contribution to Plasma Physics* 47(3), (2007), 165-172.
20. M. Radmilovic-Radjenovic, Z.Lj. Petrovic, Ž. Nikitovic, A. Strinic, V. Stojanovic, A. Nina and **B. Radjenovic**, Particle-in-cell Modelling of a Neutral Beam Source for Material Processing in Nanoscale Structures Fabrication, *Materials Science Forum* 555, (2007), 47-52.
21. **B. Radjenovic**, M. Radmilovic-Radjenovic and Z.Lj. Petrovic, Influence of Charging on SiO₂ Etching Profile Evolution Etched by Fluorocarbon Plasmas, *Materials Science Forum* 555, (2007) 53.
22. M. Radmilović-Radjenović and **B. Radjenović**, The Influence of the Magnetic Field on the Electrical Breakdown Phenomena, *Plasma Science and Technology* 9 (2007), 45-51.
23. M. Radmilović-Radjenović and **B. Radjenović**, The Effect of the Secondary Electron Production on the Microwave Breakdown Phenomena, *International Review of Physics* 1 (2007), 96-101.
24. M. Radmilović-Radjenović and **B. Radjenović**, An analytical relation describing the dramatic reduction of the breakdown voltage for the microgap devices, *Europhys. Lett.* 83 (2008), 25001 (4pp).
25. **B.M. Radjenovic**, M.D. Radmilovic-Radjenovic, Z.Lj. Petrovic, Dynamics of the Profile Charging During SiO₂ Etching in Plasma for High Aspect Ratio Trenches, *IEEE Trans. Plasma Sci.* 36 (2008) 874-875.
26. **B. Radjenović** and M. Radmilović-Radjenović, Three Dimensional Level Set Simulations of the Wet Etching of Silicon, *International Review on Modelling and Simulations* 2(3) (2009), 328-332.
27. **B. Radjenović** and M. Radmilović-Radjenović, Simulations of Surface Roughness of Nanocomposite Materials by Using Level Set Method, *International Review on Modelling and Simulations* 2, (2009), 595-598.
28. **B. Radjenović**, M. Radmilović-Radjenović, M. Mitrić, Application of the level set method in non-convex Hamiltonians, *Facta Universitatis, Series: Physics, Chemistry and Technology* 7(1), (2009), 33-44.
29. M. Radmilović-Radjenović and **B. Radjenović**, Phenomenological Approach to the Breakdown Phenomena in Radio-Frequency Microdischarges, *International Review of Physics* 3, (2009) 161-165.
30. M. Radmilović-Radjenović, **B. Radjenovic** and Z.Lj. Petrovic, Application of level set method in simulation of surface roughness in nanotechnologies, *Thin Solid Films* 517 (2009) 3954-3957.
31. **B. Radjenovic** and M. Radmilović-Radjenović, Level set simulations of 3D etching profile evolution in the anisotropic wet etching of silicon, *Thin Solid Films* 517 (2009) 4233-4237.
32. Z. Petrović, M. Radmilović-Radjenović, **B. Radjenović**, D. Marić, N. Puač, G. Malović, Plasma surface interaction in integrated circuit production and biomedical applications, *Journal of Optoelectronics and Advanced Materials* 11 (2009) 1163 – 1169.
33. R. Balvanovic, **B. Radjenovic**, P. Belicev P, N. Neskovic, Controlling FAMA by the Ptolemy II model of ion beam transport, *Nuclear instruments & methods in physics research. Section A*, 607 (2009) 322-333.
34. **B. Radjenović** and M. Radmilović-Radjenović, Level set simulations of the Anisotropic Wet Etching Process for device fabrication in Nanotechnologies, *Chemical ind.* 64(2) (2010) 93-97.

35. M. Radmilović-Radjenović and **B. Radjenović**, The effects of the chemical (isotropic) and anisotropic etch processes on roughening of the nanocomposite substrates, *Plasma Science and Technology* 12, (2010) 673-676.
36. M. Radmilović-Radjenović, **B. Radjenović** and M. Savić, Breakdown Phenomena in Water Vapor Microdischarges, *Acta Polonica A* 117(5), (2010) 752-755.
37. M. Radmilović-Radjenović, **B. Radjenović**, Determination of the etching rate from the silicon symmetry properties by extension of the level set method, *International Review of Electrical Engineering* 5, (2010), 1045-1052.
38. **B. Radjenović** and M. Radmilović-Radjenović, Application of the level set method in three-dimensional simulations of the etching profile evolution for producing nano-scale devices, *Optoelectronics and advanced materials-rapid communications* 4, (2010), 1193-1195.
39. **B. Radjenović**, M. Radmilović-Radjenović and M. Mitrić, Level set Approach to Anisotropic Wet Etching of Silicon, *Sensors* 10, (2010) 4950-4967.
40. M. Radmilović-Radjenović and **B. Radjenović**, Theoretical studies of the breakdown characteristics at microwave frequencies in small gaps, *Spectroscopy Letters* 44, (2011), 146
41. **B. Radjenović** and M. Radmilović-Radjenović, Three-dimensional simulations of the anisotropic etching profile evolution for producing nanoscale devices, *Acta Polonica A* 119, (2011), 447-450.
42. M. Klas, Š. Matejčik, **B. Radjenović** and M. Radmilović-Radjenović, Experimental and theoretical studies of the direct-current breakdown voltage in argon at micrometer separations, *Physica Scripta* 83, (2011) 045503.
43. M. Klas, Š. Matejčik, **B. Radjenović** and M. Radmilović-Radjenović, Experimental and theoretical studies of the breakdown voltage characteristics at micrometre separations in air, *Europhysics Letters* 95 (2011) 35002 .
44. M. Radmilović-Radjenović, **B. Radjenović** and M. Savić, The surface charging effects in three-dimensional simulation of the profiles of plasma-etched nanostructures, *International Journal of Numerical modelling – electronic networks devices and fields*, 24, (2011), 535.
45. **B. Radjenović**, P. Belicev and M. Radmilović-Radjenović, A Simulation Framework for the Ion Transport in Spiral Inflectors, *IEEE Transac. On Plasma Science* 39, (2011), 2612.
46. **B. Radjenović** and M. Radmilović-Radjenović, Top down technologies in surface modification of materials, *Central European Journal of Physics* 9, (2011), 265 (review article)
47. M. Radmilović-Radjenović, **B. Radjenović**, Željka Nikitović, Š. Matejčik and M. Klas, The humidity effect on the breakdown voltage characteristics and the transport parameters of air, *Nuclear Instruments and Methods in Physics Research Section B* 279 (2012), 103-106.
48. M. Klas, M. Radmilović-Radjenović, **B. Radjenović**, M. Stano and Š. Matejčik, Transport parameters and breakdown voltage characteristics of the dry air and its constituents, *Nuclear Instruments and Methods in Physics Research Section B* 279 (2012), 96-99.
49. M. Klas, Š. Matejčik, **B. Radjenović**, P. Papp and M. Radmilović-Radjenović, The breakdown voltage characteristics, the effective secondary emission coefficient and the ionization coefficient of the argon-based mixtures, *Nuclear Instruments and Methods in Physics Research Section B* 279 (2012), 100-103.
50. M. Radmilović-Radjenović, **B. Radjenović**, M. Klas and Š. Matejčik, The breakdown voltage curves in direct current discharges in molecular gases at microgaps, *Micro&Nano Letters* 7, (2012), 232-234.

51. M. Klas, Š. Matejčik, **B. Radjenović** and M. Radmilović-Radjenović, The breakdown voltage characteristics and the secondary electron production in direct-current hydrogen discharges for the gaps ranging from 1 to 100 microns, *Phys. Lett. A* 376, (2012), 1048-1052.
52. M. Radmilović-Radjenović, **B. Radjenović**, M. Klas and Š. Matejčik, The breakdown voltage curves in direct current microdischarges in molecular gases, *Modern Phys. Lett. B* 26, (2012), 1250122 (1-7).
53. R. Balvanovic, P. Belicev and **B. Radjenovic**, Modeling FAMA ion beam diagnostics by enhancing the Ptolemy II based model of ion beam transport control, *Nuclear Inst. and Methods in Physics Research A* 690, (2012), 17-26.
54. M. Radmilović-Radjenović, **B. Radjenović** and P. Belicev, Characteristics of the 2nd harmonic ECR micro plasma sources by using PIC/MCC simulations, *Acta Physica Polonica A* 122, (2012), 128-132.
55. B. Milanović, **B. Radjenović** and M. Radmilović-Radjenović, Three dimensional finite element modeling of optical microring resonators, *Phys. Scr.* T149 (2012), 014026 (1-5).
56. **B. Radjenović**, B. Milanović and M. Radmilović-Radjenović, Electric field enhancement in silicon slotted optical strip waveguides and microring resonators, *Phys. Scr.* T149 (2012), 014027 (1-5).
57. **B. Radjenović** and M. Radmilović-Radjenović, An application to the three-dimensional simulations of the Bosch process, *Journal Mater. Res.* 27, (2012), 793-798.
58. **B. Radjenović** and M. Radmilović-Radjenović, Three different mechanisms of the smoothing of the rough nanostructure, *Electronic Materials Letters* 8, (2012), 491-494.
59. **B. Radjenović** and M. Radmilović-Radjenović, The effect of different etching modes on the smoothing of the rough surfaces, *Materials Letters*, 86, (2012), 165-167.
60. M. Klas, S. Matejčik, M. Radmilovic-Radjenovic, **B. Radjenovic**, Electrical breakdown and volt-ampere characteristics in water vapor in microgaps, *Europhysics Letters*, 99, (2012), 57001 (1-4).
61. M. Radmilovic-Radjenovic, **B. Radjenovic**, S. Matejčik, M. Klas, Field-emission-driven direct current hydrogen discharges in microgaps, *Europhysics Letters*, 103, (2013), 45002(1-5).
62. M. Radmilovic-Radjenovic, S. Matejčik, M. Klas, **B. Radjenovic**, The role of the field emission effect in direct-current argon discharges for the gaps ranging from 1 to 100 μ m, *J. Phys. D: Appl. Phys.*, 46, (2013), 015302.
63. S. Matejčik, M. Klas, **B. Radjenovic**, M. Durian, M. Savic, M. Radmilovic-Radjenovic, The Role of the Field Emission Effect in the Breakdown Mechanism of Direct-Current Helium Discharges in Micrometer Gaps, *Contribution to Plasma Physics*, 53, (2013), 573-579.
64. **B. Radjenovic**, M. Radmilovic-Radjenovic, B. Belicev, Three dimensional simulations in fields and particles in software and inflector designs, *Journal of Software Engineering and Applications*, 6, (2013), 390-395.
65. M. Radmilović-Radjenović, **B. Radjenović**, M. Klas, A. Bojarov and S. Matejčik The breakdown mechanisms in electrical discharges-the role of the field emission effect in direct current discharges in microgaps, *Acta Physica Slovaca*, 63, (2013), 105 – 205.
66. M. Radmilović-Radjenović, **B. Radjenović**, M. Klas, Š. Matejčik, A semi-empirical expression for the first Townsend coefficient in strong electric fields, *Europhysics Letters* 108, (2014), 65001
67. M. Smiljanić, **B. Radjenović**, M. Radmilović-Radjenović, Ž. Lazić, V. Jović, Simulation and experimental study of maskless convex corner compensation in TMAH water solution, *J. Micromech. Microeng.* 24, (2014), 115003

68. M. Klas, Š. Matejčik, **B. Radjenović**, M. Radmilović-Radjenović, Measurements of the volt-ampere characteristics and the breakdown voltages of direct-current helium and hydrogen discharges in microgaps, *Physics of Plasmas* 21 (2014), 103503
69. **B. Radjenović**, M. Radmilović-Radjenović, The Effect of Plasma Etching on the Surface Topography of Niobium Superconducting Radio Frequency Cavities, *Electron. Mater. Lett.* 10 (2014), 1043
70. **B. Radjenović**, M. Radmilović-Radjenović, Excitation of Confined Modes in Silicon Slotted Waveguides and Microring Resonators for Sensing Purposes, *IEEE Sensors Journal* 14 (2014), 1412-1417
71. M. Radmilovic-Radjenovic, **B. Radjenović**, Š. Matejčik , M. Klas, The Breakdown Phenomena in Micrometer Scale Direct-Current Gas Discharges, *Plasma Chemistry and Plasma Processing* 34 (2014), 55-64
72. **B. Radjenović**, P. Beličev, M. Radmilović-Radjenović, Three-Dimensional Simulations of the Surface Topography Evolution of Niobium Superconducting Radio Frequency Cavities, *Nuclear Technology & Radiation Protection* 29 (2014), 97-101
73. **B. Radjenović**, M. Radmilović-Radjenović, Computer-aided design and simulation of optical microring resonators, *International Journal of Numerical Modelling: Electronic Networks, Devices and Fields* 27 (2014), 259-267
74. **B. Radjenović**, M. Radmilović-Radjenović, Three-Dimensional Simulations of SiO₂ Etching Profile Evolution, *Engineering* 6 (2014), 1-6
75. **B. Radjenović**, M. Radmilović-Radjenović, Application of the Level Set Method in Three-Dimensional Simulation of the Roughening and Smoothing of Substrates in Nanotechnologies, *World Journal of Nano Science and Engineering* 4 (2014), 84-89
76. **B. Radjenović**, M. Radmilović-Radjenović, Š. Matejčik, M. Klas, P. Beličev, The Electrical Breakdown Characteristics of the Water Vapor in Micrometer Gap Sizes, *International Research Journal of Pure & Applied Chemistry* 4 (2014), 430-436
77. **B. Radjenović**, M. Radmilović-Radjenović, P. Beličev, Application of the Level Set Method in Three-Dimensional Simulations of the Profile Evolution, *International Research Journal of Pure & Applied Chemistry* 4 (2014), 562-567
78. M. Radmilović-Radjenović, **B. Radjenović**, An analytical model of the transient thermal behaviour of semiconductor device, *International Journal of Scientific & Engineering Research* 6, (2015), 217-221
79. M. Radmilović-Radjenović, **B. Radjenović**, Studies Of The Transient Thermal Behaviour Of Semiconductor Device By Using Fourier Series, *Journal of Multidisciplinary Engineering Science and Technology* 2 (2015) 1276-1278
80. M. Sabo, B. Michalczuk, Z. Lichvanová, V. Kavický, **B. Radjenovic**, S. Matejčík, Interactions of multiple reactant ions with 2,4,6-trinitrotoluenestudied by corona discharge ion mobility-mass spectrometry, *International Journal of Mass Spectrometry* 380 (2015) 12–20
81. S. Matejčik, **B. Radjenovic**, M. Klas and M. Radmilovic-Radjenovic, Field emission driven direct current argon discharges and electrical breakdown mechanism across micron scale gaps, *Eur. Phys. J. D* 69, (2015),
82. M Klas, L Moravsky, Š Matejčik, **B. Radjenović** and M Radmilović-Radjenović, Breakdown mechanism in hydrogen microdischarges from direct-current to 13.56 MHz, *J. Phys. D: Appl. Phys.* 48 (2015) 405204
83. M. Sabo, M. Malaskova, O. Harmathova, J. Hradski, M. Masar, **B.Radjenovic** and S. Matejčík, Direct Liquid Sampling for Corona Discharge Ion Mobility Spectrometry, *Anal. Chemistry* 87, (2015), 7389-7395
84. M. Radmilovic-Radjenovic, **B. Radjenovic** and M. Savic, Microwave Field Strength Computing for the Resonator Designs and Filters, *A. Phys. Polon. A* 129, (2016), 289-292

85. M. Klas, L. Moravsky, Š. Matejčik, **B. Radjenovic**, and M. Radmilovic-Radjenovic, Fundamental Properties of the High Pressure Hydrogen Microdischarges in Static and Time-Varying Electric Fields, *IEEE Trans. Plasma Science* 45, (2017), 913-917
86. M. Klas, Š. Matejčik, L. Moravsky, **B. Radjenovic**, and M. Radmilovic-Radjenovic, Field-emission enhanced breakdown in oxygen microdischarges from direct-current to radio-frequencies, *Europhysics Letters* 120 (2017) 25002
87. M. Radjenovic and **B. Radjenovic**, The Effect of the Field Emission on the Breakdown Voltage Characteristics of Nitrogen Microdischarges, *International Journal of Engineering Innovation & Research* 6 (2017) 280-283
88. M. Radmilović- Radjenović and **B. Radjenović**, Theoretical Studies of the Electrical Discharge Characteristics of Sulfur Hexafluoride, *Journal. Electr. Eng. Technol.* 12 (2017), 288-294
89. M. Radmilovic-Radjenovic, P. Belicev and **B. Radjenovic**, Study of multipactor effect with applications to superconductive radio frequency cavities, *Nuclear Technology & Radiation Protection* 32 (2017) 115-119
90. M. Klas, L. Moravsky, Š. Matejčik, M. Zahoran, V. Martišovits, **B Radjenović** and M Radmilović-Radjenović, The breakdown voltage characteristics of compressed ambient air microdischarges from direct current to 10.2 MHz, *Plasma Sources Sci. Technol.* 26 (2017) 055023
91. **B. Radjenović**, M. Radmilović-Radjenović and P. Beličev, Eigenmodes of finite length silicon-on-insulator microring resonator arrays, *Opt. Quant. Electron.* 49, (2017), 149
92. M. Radmilović-Radjenović, **B. Radjenović**, The effect of the field emission on the breakdown voltage characteristics of air microdischarges, *American Journal of Engineering Research* 7, (2018), 237-241
93. M. Radmilović-Radjenović, P. Beličev and **B. Radjenović**, The effect of enhanced field emission on characteristics of superconducting radio frequency cavities, *Nuclear Technology & Radiation Protection* 33 (2018) 341-346
95. M. Radmilović-Radjenović, **B. Radjenović**, Eigenmode and frequency domain analysis of the third-order microring filters, *Opt. Quant. Electron.* 50, (2018), 233
96. M. M. Smiljanic, Ž. Lazic, **B. Radjenovic**, M. Radmilovic-Radjenovic and Vesna Jovic, Evolution of Si Crystallographic Planes-Etching of Square and Circle Patterns in 25 wt % TMAH, *Micromachines* 10 (2019) 102